SN54HCT273, SN74HCT273 OCTAL D-TYPE FLIP-FLOPS WITH CLEAR SCLS068C – NOVEMBER 1988 – REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- Contain Eight D-Type Flip-Flops
- Direct Clear Input
- Applications Include:
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These devices are positive-edge-triggered D-type flip-flops with a common enable input. The 'HCT273 are similar to the 'HCT377, but feature a common clear enable ($\overline{\text{CLR}}$) input instead of a latched clock.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output. The circuits are designed to prevent false clocking by transitions at CLR.

CLR 1 20 V _{CC} 1Q 2 19 8Q 1D 3 18 8D 2D 4 17 7D 2Q 5 16 7Q 3Q 6 15 6Q 3D 7 14 6D 4D 8 13 5D 4Q 9 12 5Q GND 10 11 CLK	SN74HCT273.	. DW, N (TOP VI	I, OR PW PACK/	- AGE
	1Q 1D 2D 2Q 3Q 3D 4D 4Q	3 4 5 6 7 8 9	19 8Q 18 8D 17 7D 16 7Q 15 6Q 14 6D 13 5D 12 5Q	

SN54HCT273 ... J OR W PACKAGE

SN54HCT273 . . . FK PACKAGE (TOP VIEW)



The SN54HCT273 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74HCT273 is characterized for operation from -40° C to 85° C.

	FUNCTION TABLE (each flip-flop)											
	INPUTS		OUTPUT									
CLR	CLK	D	Q									
L	Х	Х	L									
н	Ŷ	Н	Н									
н	Ŷ	L	L									
н	L	Х	Q ₀									



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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



logic diagram, each flip-flop (positive logic)





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absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, V _{CC} Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC}) (see Note 1)	
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note	
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	
Continuous current through V _{CC} or GND	
Package thermal impedance, θ_{JA} (see Note 2): DW packa	ge 97°C/W
N package	
PW packa	ge 128°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN54HCT273		SN74HCT273			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	\$ 5.5	4.5	5	5.5	V
VIH	High-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$	2	Ľ.		2			V
VIL	Low-level input voltage	V_{CC} = 4.5 V to 5.5 V	0	24	0.8	0		0.8	V
VI	Input voltage		0	1	VCC	0		VCC	V
Vo	Output voltage		0	20	VCC	0		VCC	V
tt	Input transition (rise and fall) times		0	5	500	0		500	ns
Т _А	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	ETER TEST CONDITIONS		Vee	Т	A = 25°C	;	SN54H	CT273	SN74H	CT273	UNIT	
PARAMETER			Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
Vou	$\lambda = \lambda = 0$	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V	
∨он	$V_{I} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -4 mA	4.5 V	3.98	4.30		3.7	N	3.84		v	
Vei	$\lambda = \lambda = 0$	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V	
VOL	VI = VIH or VIL	VI = VIH OL VIL	I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	v
lj	$V_I = V_{CC} \text{ or } 0$		5.5 V		±0.1	±100	7	±1000		±1000	nA	
ICC	$V_I = V_{CC} \text{ or } 0,$	IO = 0	5.5 V			8	Dn.	160		80	μA	
∆I _{CC} ‡	One input at 0.5 V Other inputs at 0 o		5.5 V		1.4	2.4	10yd	3		2.9	mA	
Ci			4.5 V to 5.5 V		3	10		10		10	pF	

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



timing requirements over recommended operating free-air temperature range (unless otherwise)
noted)	

				T _A =	25°C	SN54H	CT273	SN74H	CT273	UNIT
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f	Clock frequency		4.5 V	0	25	0	16	0	20	MHz
fclock	Clock liequency		5.5 V	0	28	0	19	0	23	
	CLK high or low	4.5 V	20		30		25			
		CLK high or low	5.5 V	18		25	ĨEV	22		-
tw Pulse duration	Fuise duration		4.5 V	16		24	<i>IEL</i>	20		ns
			5.5 V	14		20	Q	17		
		Data	4.5 V	20		30		25		
L .	Satur time before CLK [↑]	Dala	5.5 V	17		25		21		-
'su	t _{su} Setup time before CLK↑		4.5 V	20		\$ 30		25		ns
		CLR inactive	5.5 V	17		25		21		
+.	Hold time data after CLK↑		4.5 V	0		0		0		-
th			5.5 V	0		0		0		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V, C_L = 50 pF (unless otherwise noted) (see Figure 1)

				SN54HCT273					
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	Т	λ = 25°C	;	MIN	МАХ	UNIT
	((001101)		MIN	TYP	MAX	WIIIN	INIAA	
f			4.5 V	25	31		16		MHz
f _{max}			5.5 V	28	37		19		
÷ .	CLR	Apy(4.5 V		15	34		50	20
^t pd	CLR	Any	5.5 V		12	29		42	ns
t=	CLR	Apy(4.5 V		17	<u>(</u>) 15		50	20
^t PHL	CLR	Any	5.5 V		15	34		42	ns
t.		Anv	4.5 V		8	18		22	ns
tt		Any	5.5 V		7	19		21	115

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V, C_L = 50 pF (unless otherwise noted) (see Figure 1)

						SN	74HCT2	73		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	Vcc	Т	λ = 25°C	;	MIN	МАХ	UNIT	
		(001101)		MIN	TYP	MAX		WAA		
4			4.5 V	25	31		20		MHz	
f _{max}			5.5 V	28	37		23			
÷ .	CLR	Any	4.5 V		15	34		42	ns	
^t pd	CLR	Ally	5.5 V		12	29		36	115	
t =		Any	4.5 V		17	34		42	ns	
^t PHL	CLR	Any	5.5 V		15	29		36	115	
4		Anv	4.5 V		8	15		19		
tt		Any	5.5 V		7	14		17	ns	



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operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load	30	pF



- - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r = 6 ns, t_f = 6 ns.
 - C. The outputs are measured one at a time with one input transition per measurement.
 - D. For clock inputs, $f_{\mbox{max}}$ is measured when the input duty cycle is 50%.
 - E. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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